.

P20 WCDMA V_RMC12.2K_Rear Face_1.5cm_Ch4132

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 5	WCDMA, -	826.400, 4132	10.86	0.945	42.2

Hardware Setup

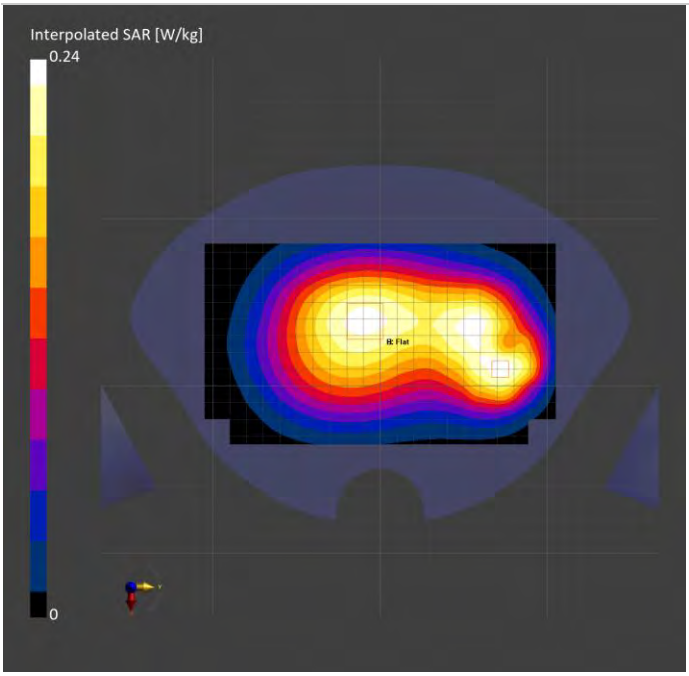
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-05-09	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-09	2025-05-09
psSAR1g [W/kg]	0.205	0.201
psSAR10g [W/kg]	0.142	0.125
Power Drift [dB]	-0.02	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.3
Dist 3dB Peak [mm]		14.5



.

P21 LTE B2_QPSK20M_Rear Face_1.5cm_Ch18900_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 2	LTE-FDD, -	1880.000, 18900	8.77	1.38	38.4

Hardware Setup

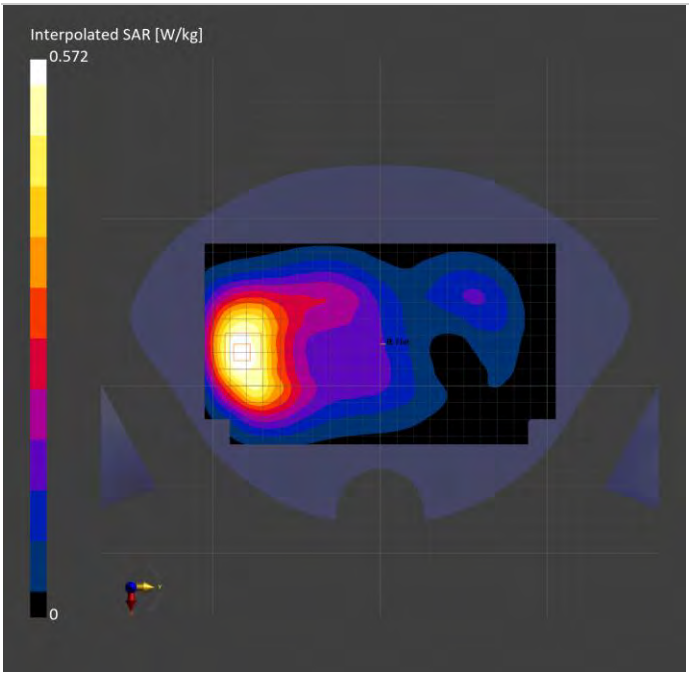
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1950-2025-05-13	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-13	2025-05-13
psSAR1g [W/kg]	0.480	0.498
psSAR10g [W/kg]	0.295	0.307
Power Drift [dB]	-0.01	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.6
Dist 3dB Peak [mm]		16.7



.

P22 LTE B7_QPSK20M_Rear Face_1.5cm_Ch20850_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 7	LTE-FDD, -	2510.000, 20850	7.90	1.83	38.1

Hardware Setup

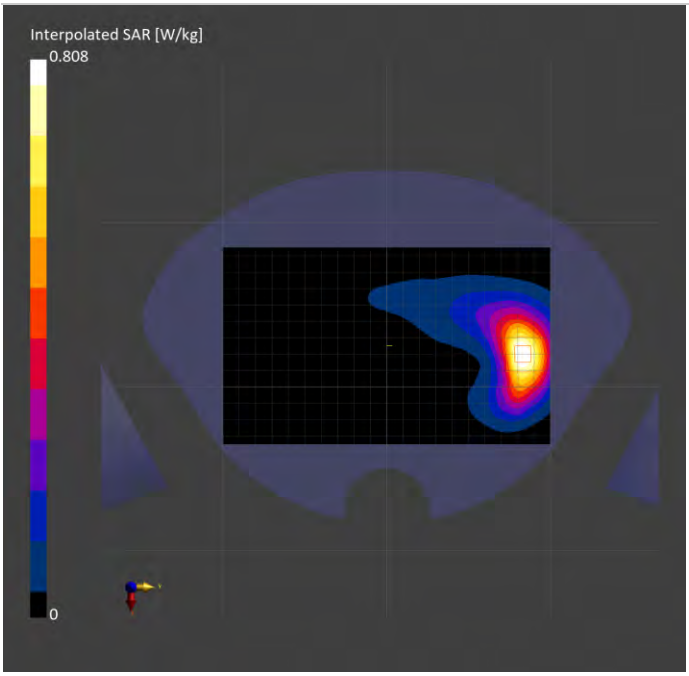
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-05-14	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-14	2025-05-14
psSAR1g [W/kg]	0.648	0.654
psSAR10g [W/kg]	0.336	0.339
Power Drift [dB]	-0.16	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.2
Dist 3dB Peak [mm]		11.5



.

P23 LTE B26_QPSK15M_Rear Face_1.5cm_Ch26965_1RB_OS37

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 26	LTE-FDD, -	841.500, 26965	10.86	0.952	42.1

Hardware Setup

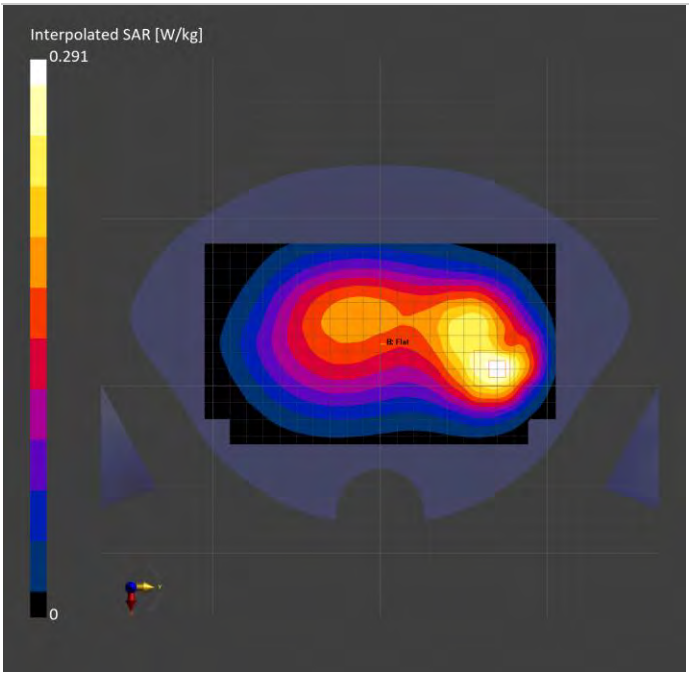
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-05-11	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-11	2025-05-11
psSAR1g [W/kg]	0.247	0.241
psSAR10g [W/kg]	0.163	0.148
Power Drift [dB]	-0.01	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.0
Dist 3dB Peak [mm]		12.8



.

P24 LTE B41_QPSK20M_Rear Face_1.5cm_Ch40620_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 41	LTE-TDD, -	2593.000, 40620	7.90	1.99	39.9

Hardware Setup

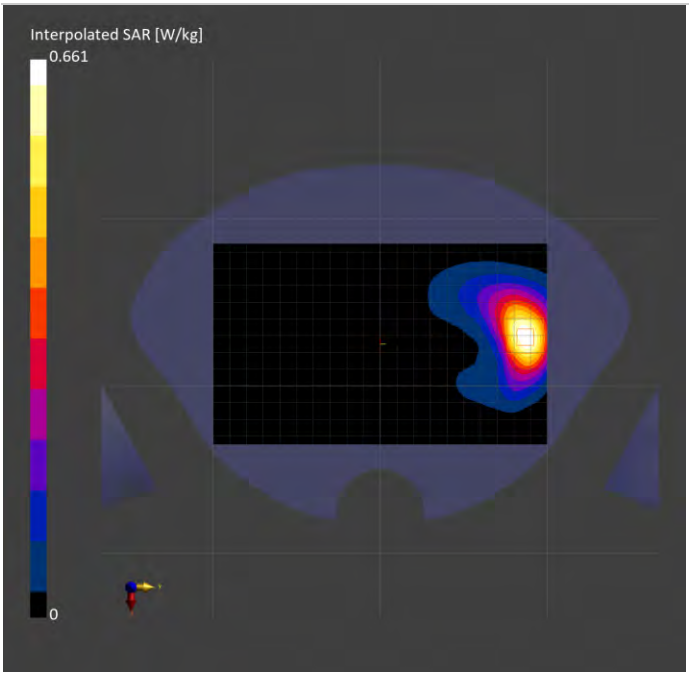
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-05-14	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-14	2025-05-14
psSAR1g [W/kg]	0.525	0.538
psSAR10g [W/kg]	0.271	0.274
Power Drift [dB]	0.02	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.2
Dist 3dB Peak [mm]		11.7



.

P25 LTE B66_QPSK20M_Rear Face_1.5cm_Ch132072_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 66	LTE-FDD, -	1720.000, 132072	9.16	1.35	41.5

Hardware Setup

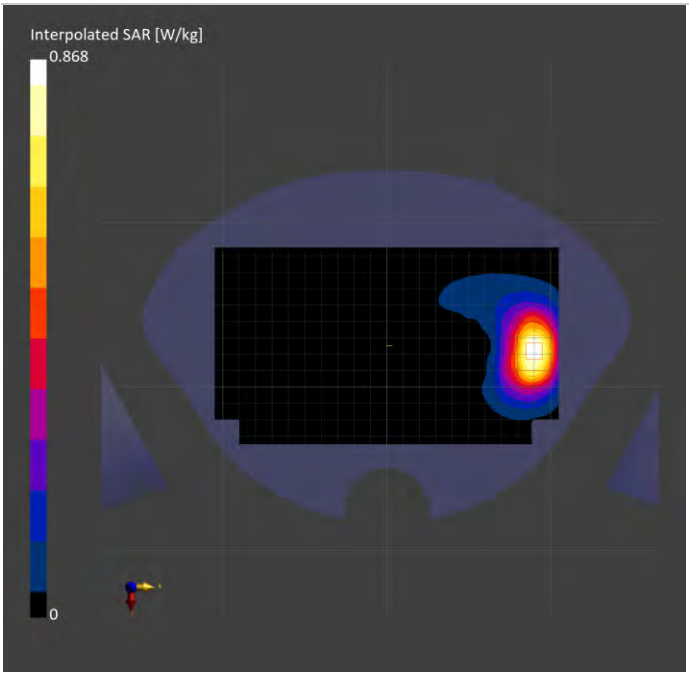
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1750-2025-05-12	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-12	2025-05-12
psSAR1g [W/kg]	0.706	0.751
psSAR10g [W/kg]	0.400	0.426
Power Drift [dB]	0.00	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.5
Dist 3dB Peak [mm]		12.0



.

P26 WLAN 2.4G_802.11b_Rear Face_1.5cm_Ch1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	WLAN 2.4GHz	WLAN, -	2412.000, 1	8.10	1.85	39.2

Hardware Setup

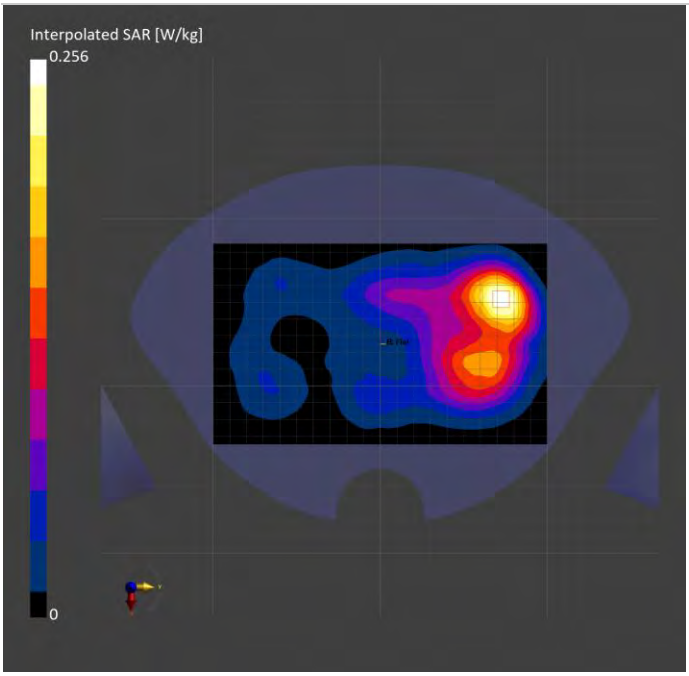
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-05-16	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-16	2025-05-16
psSAR1g [W/kg]	0.207	0.206
psSAR10g [W/kg]	0.111	0.109
Power Drift [dB]	-0.11	0.14
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.9
Dist 3dB Peak [mm]		13.0



.

P27 WLAN 5G_802.11a_Rear Face_1.5cm_Ch60

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	WLAN 5GHz	WLAN, -	5300.000, 60	4.71	4.57	36.4

Hardware Setup

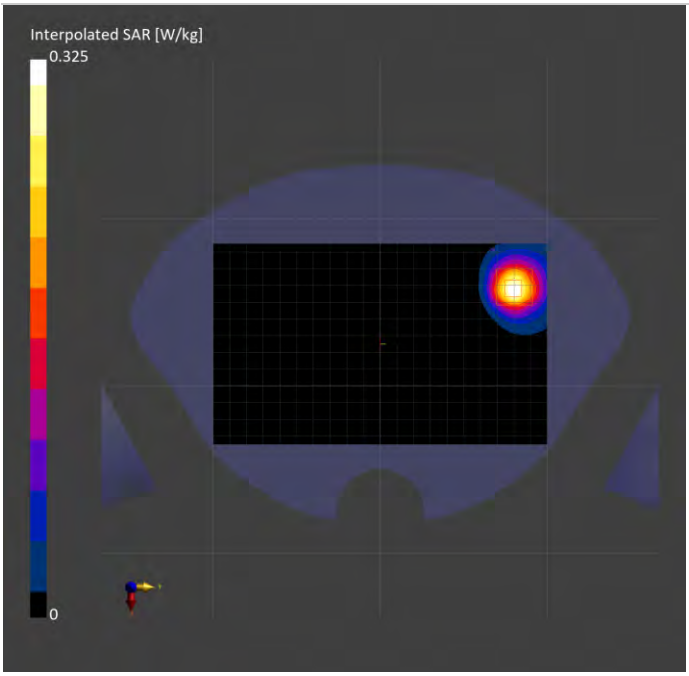
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-05-17	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-17	2025-05-17
psSAR1g [W/kg]	0.231	0.228
psSAR10g [W/kg]	0.086	0.082
Power Drift [dB]	-0.02	-0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		65.9
Dist 3dB Peak [mm]		10.6



.

P28 WLAN5G_802.11a_Rear Face_1.5cm_Ch100

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	WLAN 5GHz	WLAN, -	5500.000, 100	5.07	4.79	36.0

Hardware Setup

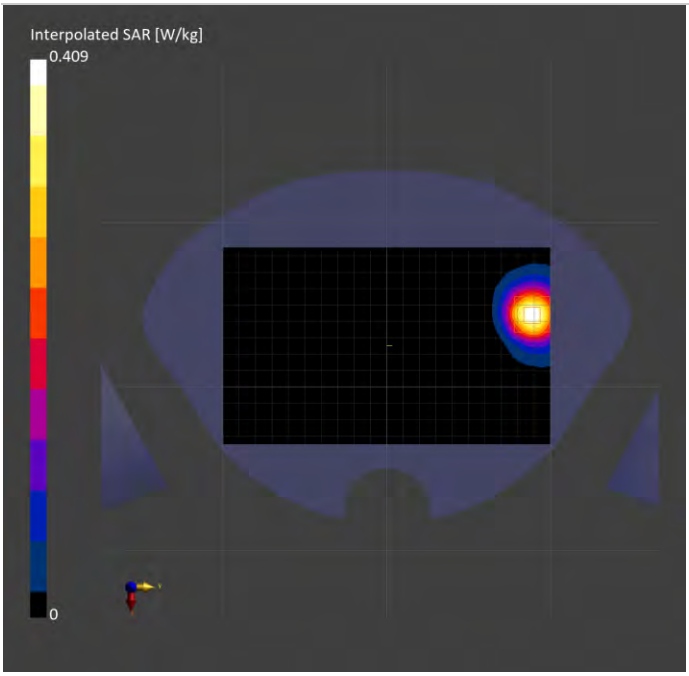
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-05-18	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-18	2025-05-18
psSAR1g [W/kg]	0.298	0.301
psSAR10g [W/kg]	0.115	0.114
Power Drift [dB]	0.08	-0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		63.4
Dist 3dB Peak [mm]		11.9



.

P29 WLAN 5G_802.11a_Rear Face_1.5cm_Ch149

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	WLAN 5GHz	WLAN, -	5745.000, 149	5.21	5.07	35.6

Hardware Setup

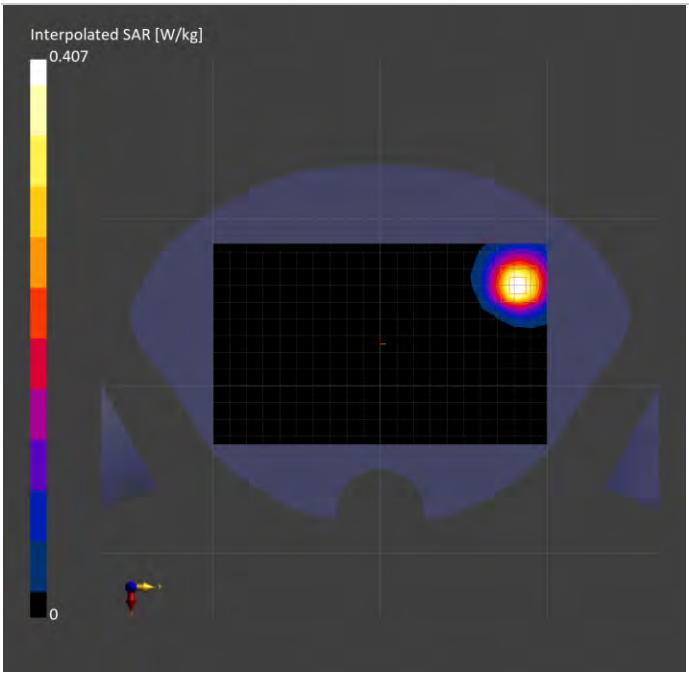
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-05-19	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-19	2025-05-19
psSAR1g [W/kg]	0.306	0.307
psSAR10g [W/kg]	0.117	0.114
Power Drift [dB]	0.01	-0.14
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		63.6
Dist 3dB Peak [mm]		11.2



.

P30 BT_GFSK_Rear Face_1.5cm_Ch39

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	ISM 2.4 GHz Band	Bluetooth, -	2441.000, 39	8.10	1.87	39.1

Hardware Setup

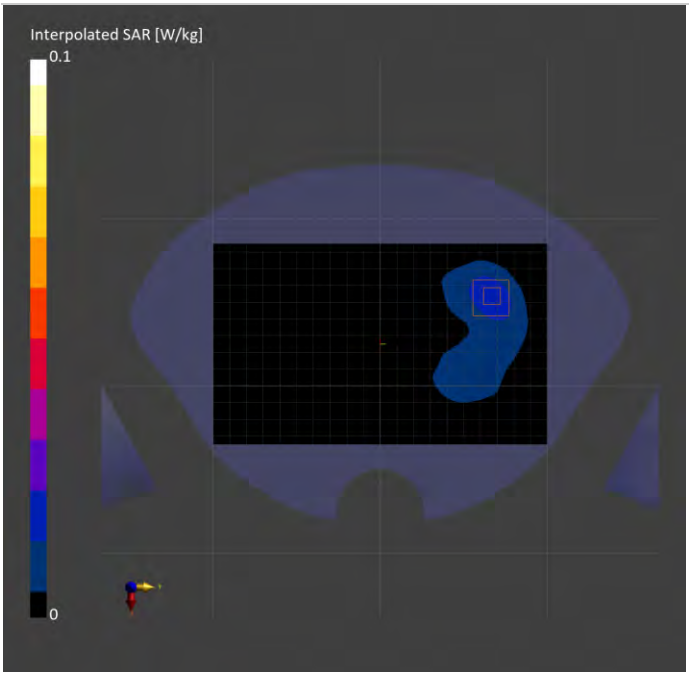
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-05-16	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-16	2025-05-16
psSAR1g [W/kg]	0.018	0.019
psSAR10g [W/kg]	0.01	0.01
Power Drift [dB]	-0.16	-0.19
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.4
Dist 3dB Peak [mm]		12.8



.

P31 GSM850_GPRS 1Tx Slot_Rear Face_1cm_Ch251

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	GSM 850	GSM, -	848.800, 251	10.86	0.955	42.1

Hardware Setup

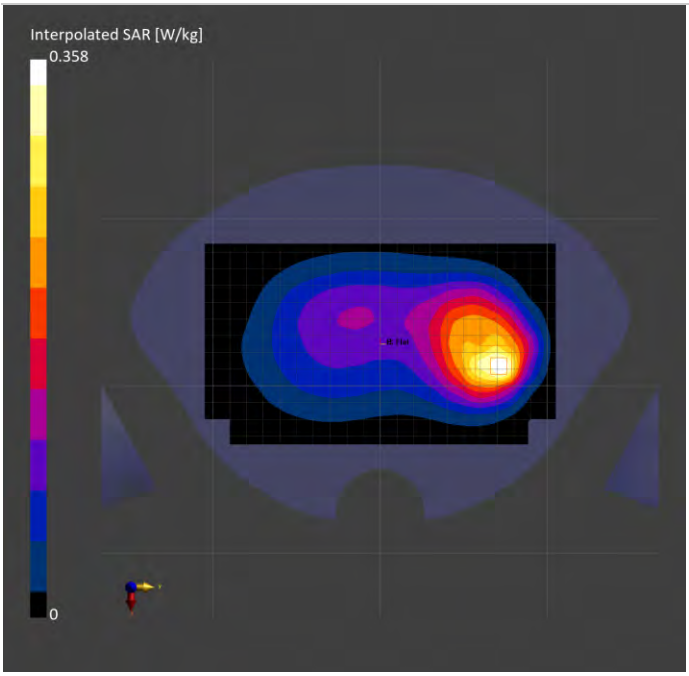
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-05-09	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-09	2025-05-09
psSAR1g [W/kg]	0.299	0.288
psSAR10g [W/kg]	0.189	0.165
Power Drift [dB]	0.01	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.0
Dist 3dB Peak [mm]		10.2



.

P32 GSM1900_GPRS 1Tx Slot_Bottom Side_1cm_Ch661

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	PCS 1900	GSM, -	1880.000, 661	8.77	1.38	38.4

Hardware Setup

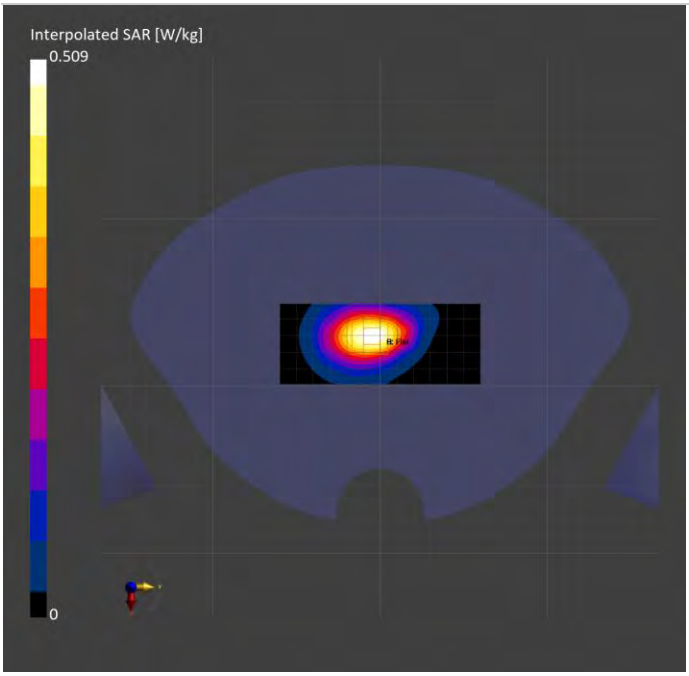
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1950-2025-05-13	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-13	2025-05-13
psSAR1g [W/kg]	0.414	0.422
psSAR10g [W/kg]	0.227	0.235
Power Drift [dB]	-0.00	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.8
Dist 3dB Peak [mm]		12.0



.

P33 WCDMA II_RMC12.2K_Bottom Side_1cm_Ch9262

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band 2	WCDMA, -	1852.400, 9262	8.77	1.36	38.5

Hardware Setup

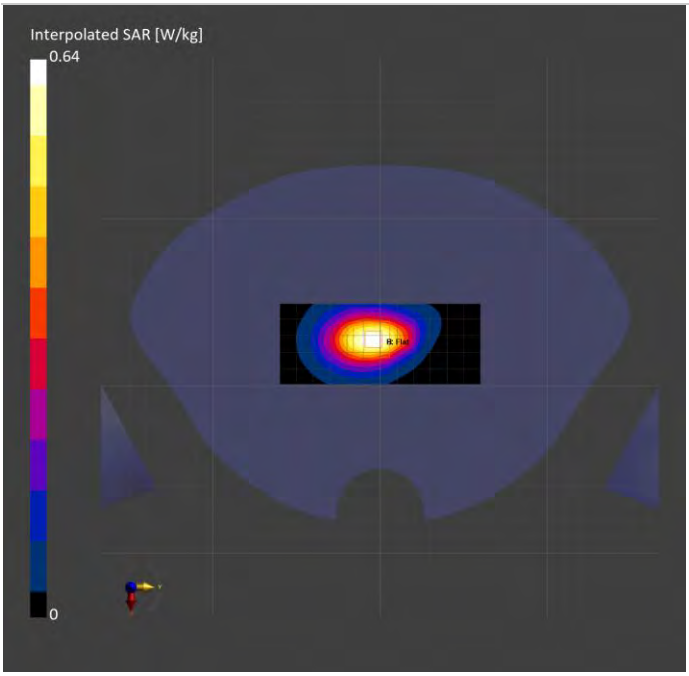
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1950-2025-05-13	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-13	2025-05-13
psSAR1g [W/kg]	0.518	0.533
psSAR10g [W/kg]	0.284	0.298
Power Drift [dB]	0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.2
Dist 3dB Peak [mm]		12.0



.

P34 WCDMA IV_RMC12.2K_Bottom Side_1cm_Ch1513

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band 4	WCDMA, -	1752.600, 1513	9.16	1.36	41.5

Hardware Setup

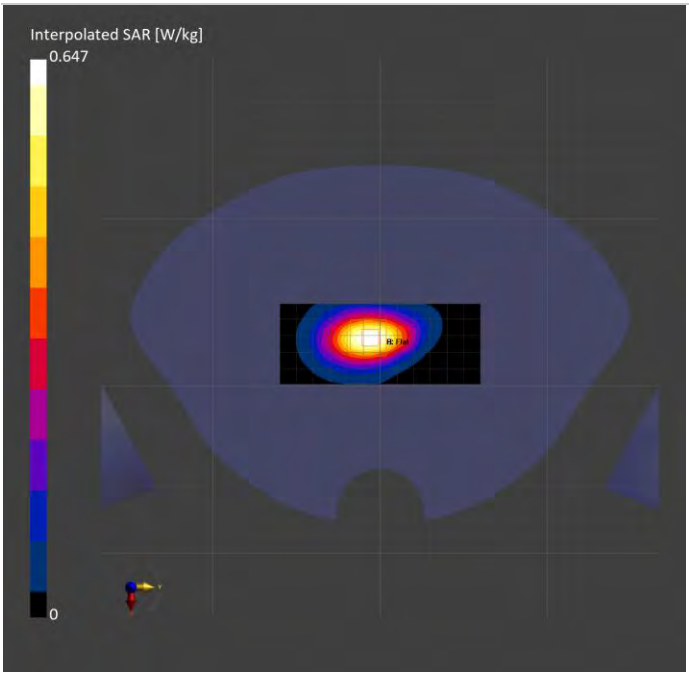
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1750-2025-05-12	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-12	2025-05-12
psSAR1g [W/kg]	0.526	0.543
psSAR10g [W/kg]	0.291	0.305
Power Drift [dB]	0.01	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.4
Dist 3dB Peak [mm]		11.9



.

P35 WCDMA V_RMC12.2K_Rear Face_1cm_Ch4233

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 5	WCDMA, -	846.600, 4233	10.86	0.954	42.1

Hardware Setup

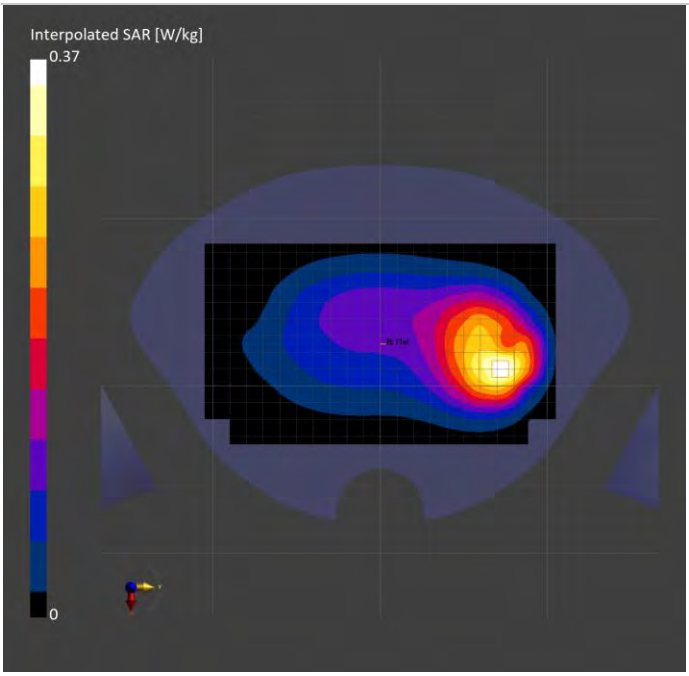
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-05-09	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-09	2025-05-09
psSAR1g [W/kg]	0.310	0.303
psSAR10g [W/kg]	0.198	0.176
Power Drift [dB]	-0.01	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		76.6
Dist 3dB Peak [mm]		10.2



.

P36 LTE B2_QPSK20M_Bottom Side_1cm_Ch18900_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band 2	LTE-FDD, -	1880.000, 18900	8.77	1.38	38.4

Hardware Setup

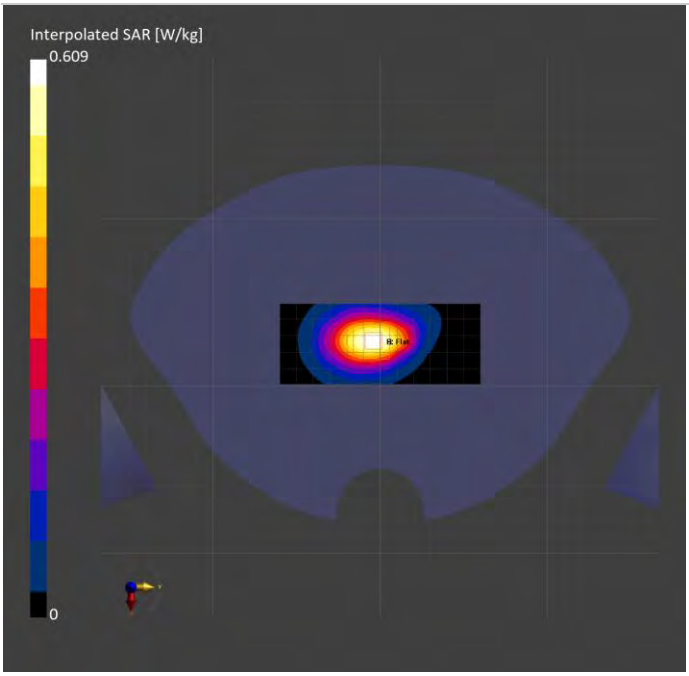
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1950-2025-05-13	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-13	2025-05-13
psSAR1g [W/kg]	0.493	0.505
psSAR10g [W/kg]	0.271	0.284
Power Drift [dB]	0.02	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.1
Dist 3dB Peak [mm]		12.3



.

P37 LTE B7_QPSK20M_Bottom Side_1cm_Ch21350_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band 7	LTE-FDD, -	2560.000, 21350	7.90	1.96	40.0

Hardware Setup

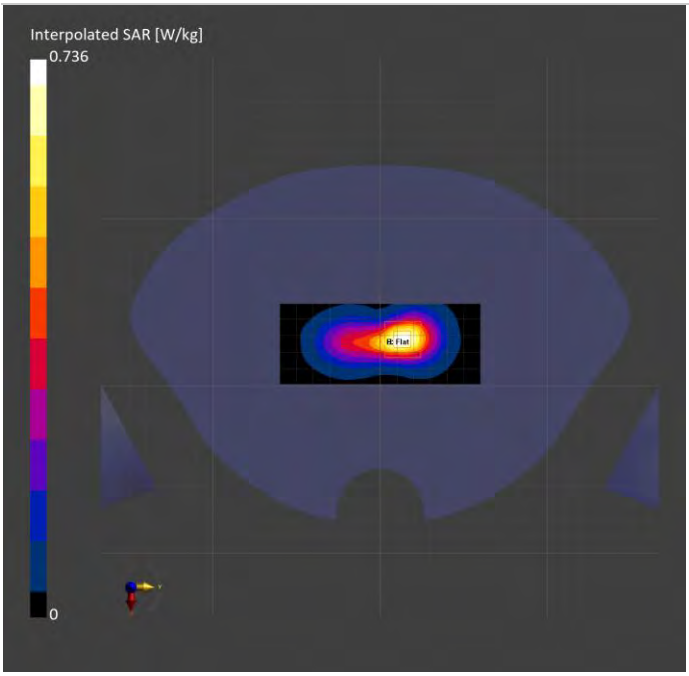
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-05-14	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-14	2025-05-14
psSAR1g [W/kg]	0.561	0.587
psSAR10g [W/kg]	0.264	0.276
Power Drift [dB]	0.02	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.6
Dist 3dB Peak [mm]		9.0



.

P38 LTE B26_QPSK15M_Rear Face_1cm_Ch26965_1RB_OS37

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 26	LTE-FDD, -	841.500, 26965	10.86	0.952	42.1

Hardware Setup

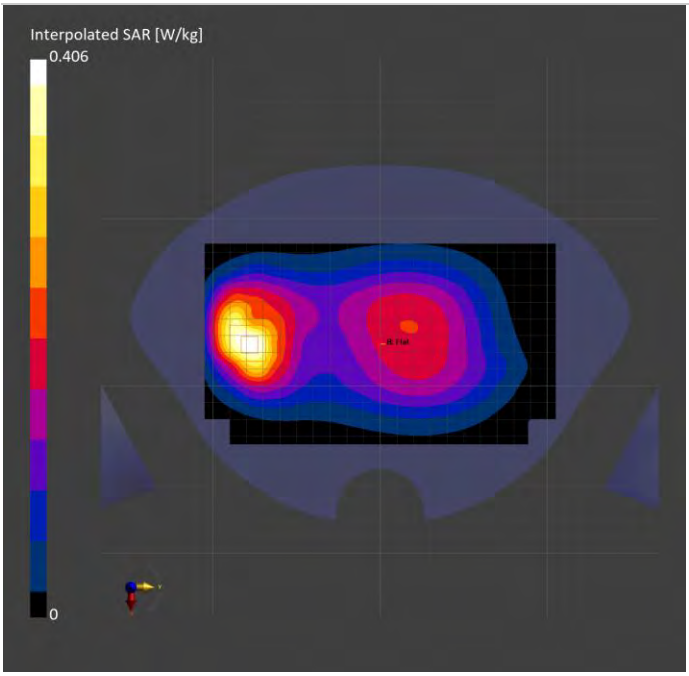
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-05-11	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-11	2025-05-11
psSAR1g [W/kg]	0.349	0.365
psSAR10g [W/kg]	0.225	0.209
Power Drift [dB]	-0.02	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.2
Dist 3dB Peak [mm]		12.4



.

P39 LTE B41_QPSK20M_Bottom Side_1cm_Ch40620_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band 41	LTE-TDD, -	2593.000, 40620	7.90	1.99	39.9

Hardware Setup

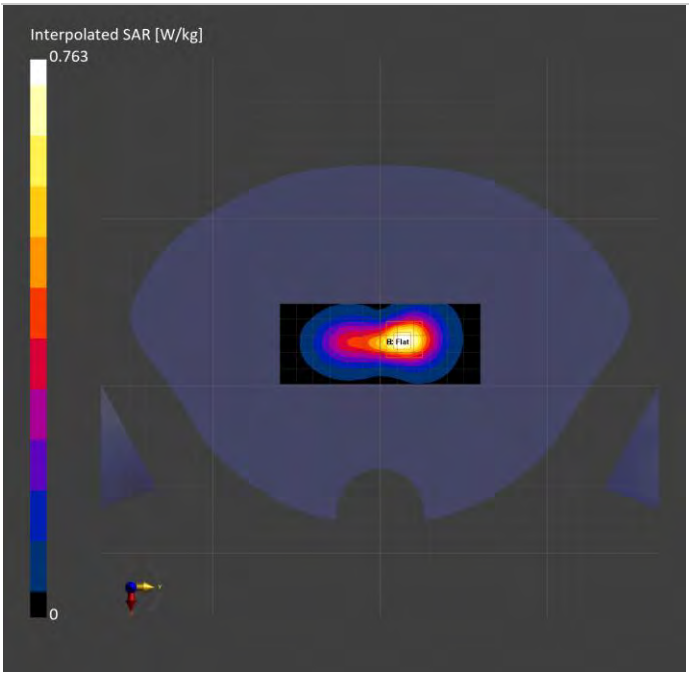
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-05-14	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-14	2025-05-14
psSAR1g [W/kg]	0.581	0.610
psSAR10g [W/kg]	0.274	0.284
Power Drift [dB]	-0.00	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		76.2
Dist 3dB Peak [mm]		9.0



.

P40 LTE B66_QPSK20M_Bottom Side_1cm_Ch132572_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band 66	LTE-FDD, -	1770.000, 132572	9.16	1.37	41.5

Hardware Setup

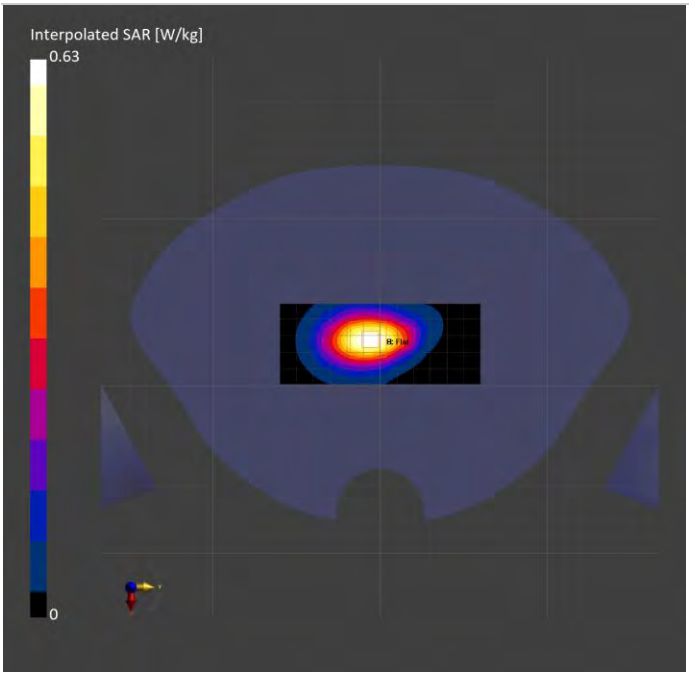
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1750-2025-05-12	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-12	2025-05-12
psSAR1g [W/kg]	0.512	0.528
psSAR10g [W/kg]	0.284	0.299
Power Drift [dB]	0.01	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.9
Dist 3dB Peak [mm]		12.0



.

P41 WLAN 2.4G_802.11b_Rear Face_1cm_Ch1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	WLAN 2.4GHz	WLAN, -	2412.000, 1	8.10	1.85	39.2

Hardware Setup

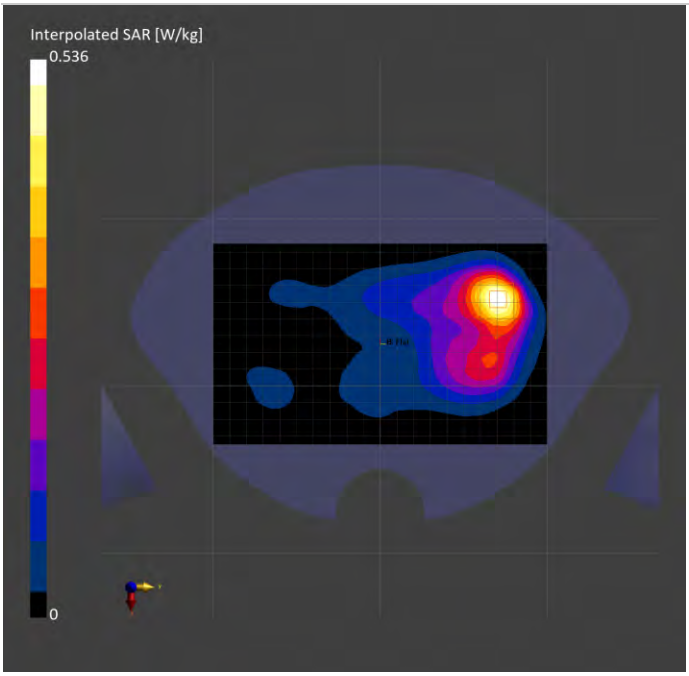
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-05-16	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-16	2025-05-16
psSAR1g [W/kg]	0.425	0.433
psSAR10g [W/kg]	0.222	0.220
Power Drift [dB]	0.12	-0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.8
Dist 3dB Peak [mm]		12.6



.

P42 WLAN 5G_802.11a_Top side_1cm_Ch48

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 10.00	WLAN 5GHz	WLAN, -	5240.000, 48	5.71	4.51	36.5

Hardware Setup

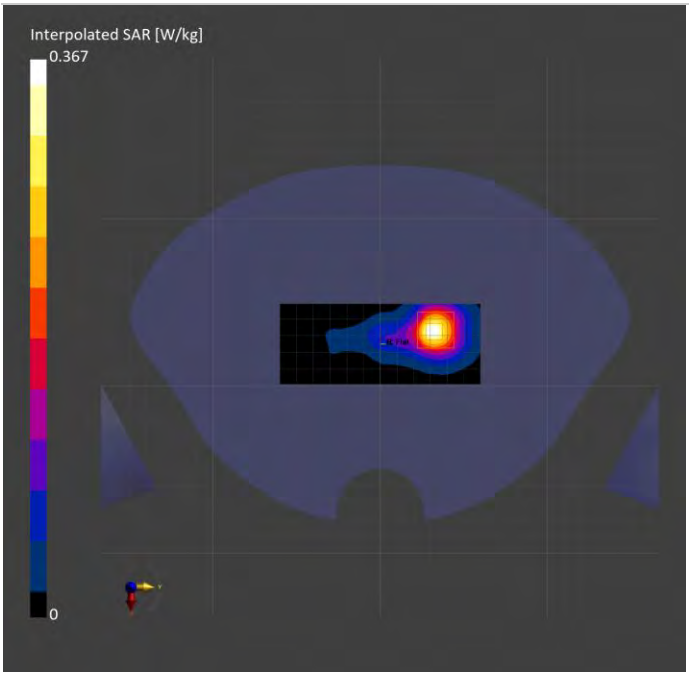
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-05-17	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-17	2025-05-17
psSAR1g [W/kg]	0.250	0.279
psSAR10g [W/kg]	0.092	0.10
Power Drift [dB]	0.01	-0.13
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		61.9
Dist 3dB Peak [mm]		10.2



.

P43 WLAN 5G_802.11a_Rear Face_1cm_Ch149

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	WLAN 5GHz	WLAN, -	5745.000, 149	5.10	5.07	35.6

Hardware Setup

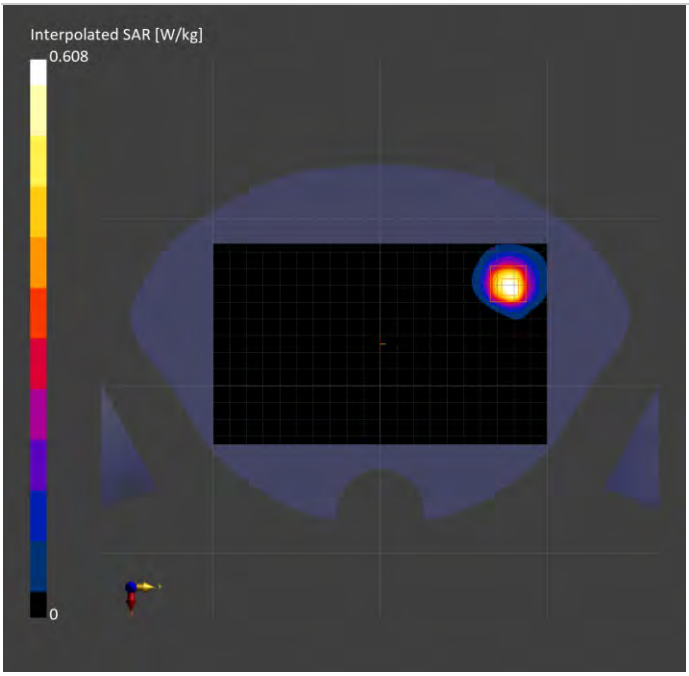
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-05-18	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-18	2025-05-18
psSAR1g [W/kg]	0.447	0.486
psSAR10g [W/kg]	0.155	0.160
Power Drift [dB]	-0.01	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		61.1
Dist 3dB Peak [mm]		8.3



.

P44 BT_GFSK_Rear Face_1cm_Ch39

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	ISM 2.4 GHz Band	Bluetooth, -	2441.000, 39	8.10	1.87	39.1

Hardware Setup

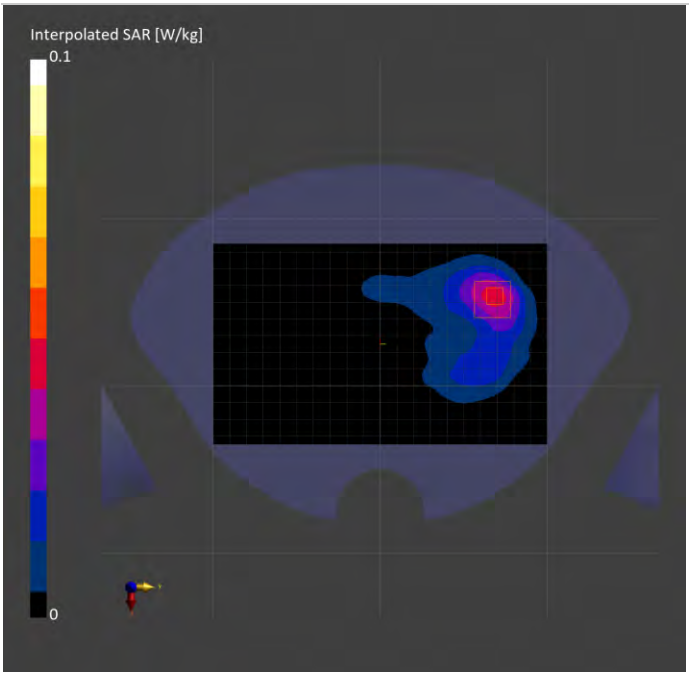
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-05-19	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-19	2025-05-19
psSAR1g [W/kg]	0.038	0.037
psSAR10g [W/kg]	0.020	0.018
Power Drift [dB]	-0.10	-0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.3
Dist 3dB Peak [mm]		13.1



.

P45 GSM1900_GPRS 1Tx Slot_Top Side_0cm_Ch512

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 0.00	PCS 1900	GSM, -	1850.200, 512	8.77	1.36	38.5

Hardware Setup

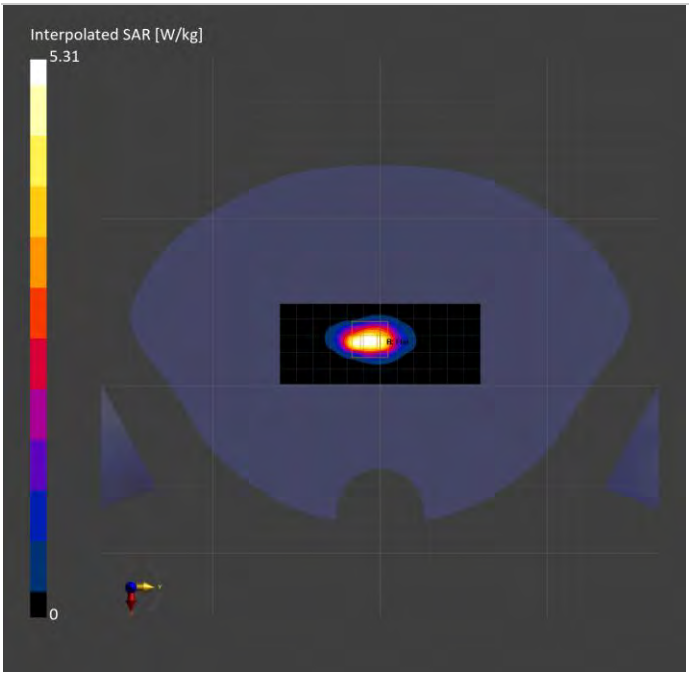
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1950-2025-05-13	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-13	2025-05-13
psSAR1g [W/kg]	4.08	4.19
psSAR10g [W/kg]	1.76	1.66
Power Drift [dB]	0.01	0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		72.2
Dist 3dB Peak [mm]		4.8



.

P46 WCDMA II_RMC12.2K_Top Side_0cm_Ch9262

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 0.00	Band 2	WCDMA, -	1852.400, 9262	8.77	1.36	38.5

Hardware Setup

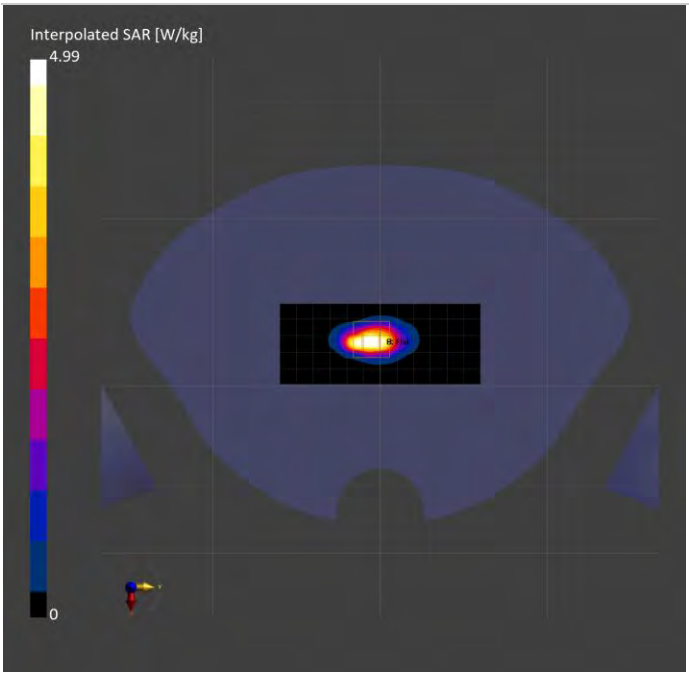
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1950-2025-05-13	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-13	2025-05-13
psSAR1g [W/kg]	3.84	3.78
psSAR10g [W/kg]	1.64	1.52
Power Drift [dB]	0.00	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		72.7
Dist 3dB Peak [mm]		5.4



.

P47 WCDMA IV_RMC12.2K_Top Side_0cm_Ch1312

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 0.00	Band 4	WCDMA, -	1712.400, 1312	9.16	1.34	41.5

Hardware Setup

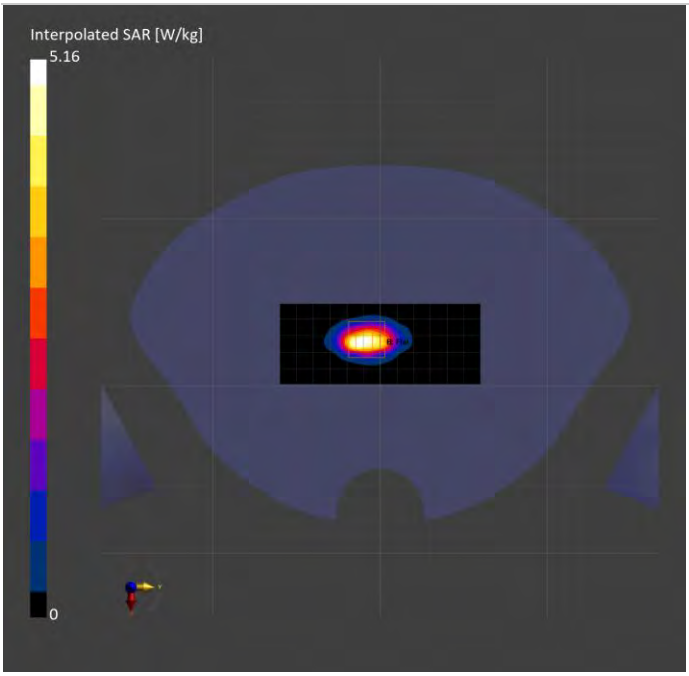
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1750-2025-05-12	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-12	2025-05-12
psSAR1g [W/kg]	3.86	3.76
psSAR10g [W/kg]	1.68	1.45
Power Drift [dB]	0.01	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		75.2
Dist 3dB Peak [mm]		4.2



.

P48 LTE B2_QPSK20M_Top Side_0cm_Ch18700_50RB_OS25

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 0.00	Band 2	LTE-FDD, -	1860.000, 18700	8.77	1.37	38.5

Hardware Setup

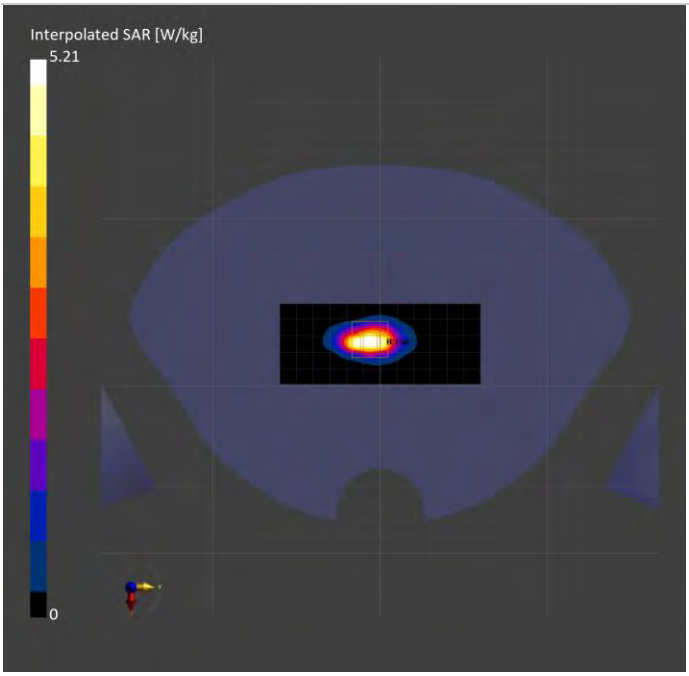
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1950-2025-05-13	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-13	2025-05-13
psSAR1g [W/kg]	4.00	4.03
psSAR10g [W/kg]	1.72	1.64
Power Drift [dB]	0.00	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		73.2
Dist 3dB Peak [mm]		5.4



.

P49 LTE B7_QPSK20M_Rear Face_0cm_Ch20850_50RB_OS25

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band 7	LTE-FDD, -	2510.000, 20850	7.90	1.92	40.1

Hardware Setup

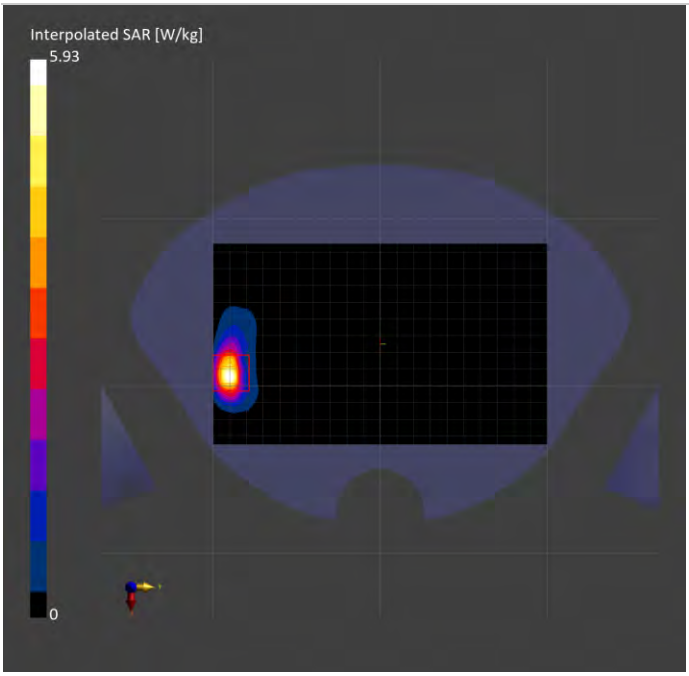
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-05-14	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-14	2025-05-14
psSAR1g [W/kg]	4.04	4.00
psSAR10g [W/kg]	1.55	1.37
Power Drift [dB]	-0.00	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		71.6
Dist 3dB Peak [mm]		4.9



.

P50 LTE B41_QPSK20M_Rear Face_0cm_Ch39750_50RB_OS25

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band 41	LTE-TDD, -	2506.000, 39750	7.90	1.93	39.0

Hardware Setup

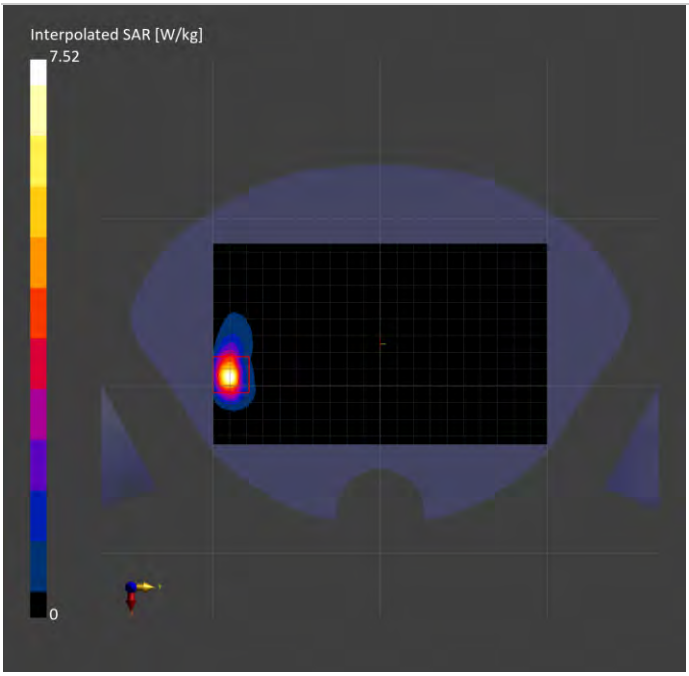
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-05-14	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-14	2025-05-14
psSAR1g [W/kg]	4.90	4.94
psSAR10g [W/kg]	1.77	1.55
Power Drift [dB]	0.00	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		66.2
Dist 3dB Peak [mm]		4.6



.

P51 LTE B66_QPSK20M_Bottom Side_0cm_Ch132572_100RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 0.00	Band 66	LTE-FDD, -	1770.000, 132572	9.16	1.37	41.5

Hardware Setup

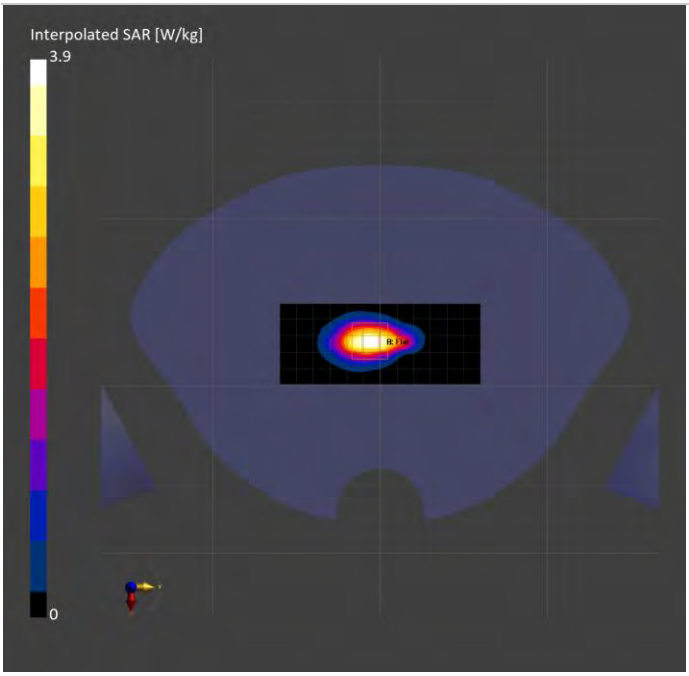
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1750-2025-05-12	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-12	2025-05-12
psSAR1g [W/kg]	3.07	3.23
psSAR10g [W/kg]	1.49	1.49
Power Drift [dB]	0.02	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		73.8
Dist 3dB Peak [mm]		6.9



.

P52 WLAN 5G_802.11a_Top side_0cm_Ch60

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 0.00	WLAN 5GHz	WLAN, -	5300.000, 60	5.71	4.57	36.4

Hardware Setup

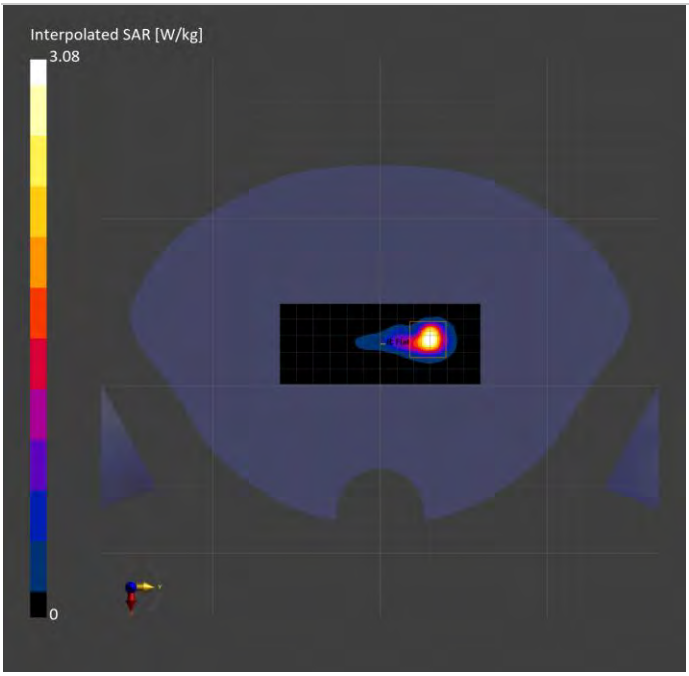
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-05-17	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-17	2025-05-17
psSAR1g [W/kg]	1.95	2.26
psSAR10g [W/kg]	0.533	0.558
Power Drift [dB]	-0.04	-0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		59.9
Dist 3dB Peak [mm]		5.6



.

P53 WLAN 5G_802.11a_Top side_0cm_Ch100

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	170.0 x 78.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 0.00	WLAN 5GHz	WLAN, -	5500.000, 100	5.10	4.79	36.0

Hardware Setup

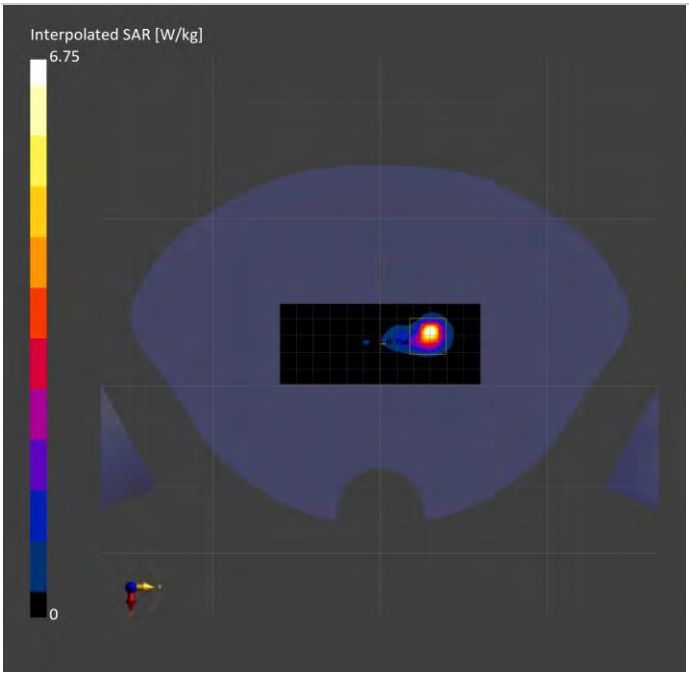
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-05-18	EX3DV4 - SN7612, 2025-05-07	DAE4 Sn1633, 2025-04-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	8.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-05-18	2025-05-18
psSAR1g [W/kg]	3.61	3.52
psSAR10g [W/kg]	0.900	0.818
Power Drift [dB]	-0.04	0.12
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		62.3
Dist 3dB Peak [mm]		4.7



Appendix C. Calibration Certificate for Probe and Dipole

The SPEAG calibration certificates are shown as follows.

In Collaboration with
CALIBRATION LABORATORY
Add: No.52 HuaYuanBei Road, Haidian District, Beijing, 100191, China
Tel: +86-10-62304633-2117
E-mail: emf@caict.ac.cn http://www.caict.ac.cn

CALIBRATION
CNAS L0570

Client : 7layers Certificate No: 25J02Z000225

CALIBRATION CERTIFICATE

Object	DAE4 - SN: 1633
Calibration Procedure(s)	FF-Z11-002-01 Calibration Procedure for the Data Acquisition Electronics (DAEx)
Calibration date:	April 24, 2025

This calibration Certificate documents the traceability to national standards, which realize the physical units of measurements(SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature(22±3)℃ and humidity<70%.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID #	Cal Date(Calibrated by, Certificate No.)	Scheduled Calibration
Process Calibrator 753	1971018	11-Jun-24 (CTTL, No.24J02X005147)	Jun-25

	Name	Function	Signature
Calibrated by:	Yu Zongying	SAR Test Engineer	
Reviewed by:	Lin Jun	SAR Test Engineer	
Approved by:	Qi Dianyuan	SAR Project Leader	

Issued: May 01, 2025

Add: No.52 HuaYuanBei Road, Haidian District, Beijing, 100191, China
Tel: +86-10-62304633-2117
E-mail: emf@caict.ac.cn http://www.caict.ac.cn

Glossary:

DAE	data acquisition electronics
Connector angle	information used in DASY system to align probe sensor X to the robot coordinate system.

Methods Applied and Interpretation of Parameters:

- *DC Voltage Measurement*: Calibration Factor assessed for use in DASY system by comparison with a calibrated instrument traceable to national standards. The figure given corresponds to the full scale range of the voltmeter in the respective range.

- *Connector angle*: The angle of the connector is assessed measuring the angle mechanically by a tool inserted. Uncertainty is not required.

- The report provide only calibration results for DAE, it does not contain other performance test results.

Add: No.52 HuaYuanBei Road, Haidian District, Beijing, 100191, China
Tel: +86-10-62304633-2117
E-mail: emf@caict.ac.cn http://www.caict.ac.cn

DC Voltage Measurement

A/D - Converter Resolution nominal

High Range: 1LSB = 6.1μV , full range = -100...+300 mV
Low Range: 1LSB = 61nV , full range = -1.....+3mV

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

Calibration Factors	X	Y	Z
High Range	405.294 ± 0.15% (k=2)	405.573 ± 0.15% (k=2)	405.072 ± 0.15% (k=2)
Low Range	4.00084 ± 0.7% (k=2)	4.00049 ± 0.7% (k=2)	4.01174 ± 0.7% (k=2)

Connector Angle

Connector Angle to be used in DASY system	318° ± 1 °

In Collaboration with
CALIBRATION LABORATORY
Add: No.52 HuaYuanBei Road, Haidian District, Beijing, 100191, China
Tel: +86-10-62304633-2117
E-mail: emf@caict.ac.cn http://www.caict.ac.cn

CALIBRATION CNAS L0570

Client 7layers Certificate No: 25J02Z000224

CALIBRATION CERTIFICATE

Object EX3DV4 - SN : 7612

Calibration Procedure(s) FF-Z11-004-02
Calibration Procedures for Dosimetric E-field Probes

Calibration date: May 07, 2025

This calibration Certificate documents the traceability to national standards, which realize the physical units of measurements(SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.
All calibrations have been conducted in the closed laboratory facility: environment temperature(22±3)℃ and humidity<70%.
Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID #	Cal Date(Calibrated by, Certificate No.)	Scheduled Calibration
Power Meter NRP2	106277	18-Oct-24(CTTL, No.24J02X101459)	Oct-25
Power sensor NRP8S	104291	18-Oct-24(CTTL, No.24J02X101459)	Oct-25
Power sensor NRP8S	104292	18-Oct-24(CTTL, No.24J02X101459)	Oct-25
Reference 10dBAttenuator	18N50W-10dB	22-Jan-25(CTTL, No.25J02X000465)	Jan-27
Reference 20dBAttenuator	18N50W-20dB	22-Jan-25(CTTL, No.25J02X000466)	Jan-27
Reference Probe EX3DV4	SN 7464	28-Jan-25(SPEAG, No.EX-7464_Jan25)	Jan-26
DAE4	SN 1555	16-Aug-24(SPEAG, No.DAE4-1555_Aug24)	Aug-25
Secondary Standards	**ID #**	**Cal Date(Calibrated by, Certificate No.)**	**Scheduled Calibration**
SignalGenerator MG3700A	6201052605	12-Jun-24(CTTL, No.24J02X005419)	Jun-25
SignalGenerator APSIN26G	181-33A6D0700-1959	27-Mar-25(CTTL, No.25J02X001962)	Mar-26
Network Analyzer E5071C	MY46110673	18-Dec-24(CTTL, No.24J02X103932)	Dec-25
Reference 10dBAttenuator	BT0520	11-May-23(CTTL, No.J23X04061)	May-25
Reference 20dBAttenuator	BT0267	11-May-23(CTTL, No.J23X04062)	May-25
OCP DAKS	SN 0015	09-Oct-24(SPEAG, No. OCP-DAKS-0015_Oct24)	Oct-25

	Name	Function	Signature
Calibrated by:	Yu Zongying	SAR Test Engineer	
Reviewed by:	Lin Jun	SAR Test Engineer	
Approved by:	Qi Dianyuan	SAR Project Leader	

Issued: May 13, 2025

Add: No.52 HuaYuanBei Road, Haidian District, Beijing, 100191, China
Tel: +86-10-62304633-2117
E-mail: emf@caict.ac.cn http://www.caict.ac.cn

Glossary:

TSL	tissue simulating liquid
NORMx,y,z	sensitivity in free space
ConvF	sensitivity in TSL / NORMx,y,z
DCP	diode compression point
CF	crest factor (1/duty_cycle) of the RF signal
A,B,C,D	modulation dependent linearization parameters
Polarization Φ	Φ rotation around probe axis
Polarization θ	θ rotation around an axis that is in the plane normal to probe axis (at measurement center), i θ=0 is normal to probe axis
Connector Angle	information used in DASY system to align probe sensor X to the robot coordinate system

Calibration is Performed According to the Following Standards:

a) IEEE Std 1528-2013, "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", June 2013

b) IEC 62209-1, "Measurement procedure for the assessment of Specific Absorption Rate (SAR) from hand-held and body-mounted devices used next to the ear (frequency range of 300 MHz to 6 GHz)", July 2016

c) IEC 62209-2, "Procedure to determine the Specific Absorption Rate (SAR) for wireless communication devices used in close proximity to the human body (frequency range of 30 MHz to 6 GHz)", March 2010

d) KDB 865664, "SAR Measurement Requirements for 100 MHz to 6 GHz"

Methods Applied and Interpretation of Parameters:

- *NORMx,y,z:* Assessed for E-field polarization θ=0 (f≤900MHz in TEM-cell; f>1800MHz: waveguide). NORMx,y,z are only intermediate values, i.e., the uncertainties of NORMx,y,z does not effect the E^2-field uncertainty inside TSL (see below ConvF).
- *NORM(f)x,y,z = NORMx,y,z* frequency_response* (see Frequency Response Chart). This linearization is implemented in DASY4 software versions later than 4.2. The uncertainty of the frequency response is included in the stated uncertainty of ConvF.
- *DCPx,y,z:* DCP are numerical linearization parameters assessed based on the data of power sweep (no uncertainty required). DCP does not depend on frequency nor media.
- PAR: PAR is the Peak to Average Ratio that is not calibrated but determined based on the signal characteristics.
- *Ax,y,z; Bx,y,z; Cx,y,z;VRx,y,z:*A,B,C are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the maximum calibration range expressed in RMS voltage across the diode.
- *ConvF and Boundary Effect Parameters:* Assessed in flat phantom using E-field (or Temperature Transfer Standard for f≤800MHz) and inside waveguide using analytical field distributions based on power measurements for f >800MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty valued are given. These parameters are used in DASY4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to NORMx,y,z* ConvF whereby the uncertainty corresponds to that given for ConvF. A frequency dependent ConvF is used in DASY version 4.4 and higher which allows extending the validity from±50MHz to±100MHz.
- *Spherical isotropy (3D deviation from isotropy):* in a field of low gradients realized using a flat phantom exposed by a patch antenna.
- *Sensor Offset:* The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.
- *Connector Angle:* The angle is assessed using the information gained by determining the *NORMx* (no uncertainty required).

In Collaboration with
s p e a g
CALIBRATION LABORATORY

CAICT

Add: No.52 HuaYuanBei Road, Haidian District, Beijing, 100191, China
Tel: +86-10-62304633-2117
E-mail: emf@caict.ac.cn http://www.caict.ac.cn

DASY/EASY – Parameters of Probe: EX3DV4 – SN: 7612

Basic Calibration Parameters

	Sensor X	Sensor Y	Sensor Z	Unc (*k*=2)
Norm(μV/(V/m)²)[A]	0.66	0.70	0.81	±10.0%
DCP(mV)[B]	114.2	115.0	115.7	

Calibration Results for Modulation Response

UID	Communication System Name		A dB	B dB√μV	C	D dB	VR mV	Max Dev.	Max Unc[E] (*k*=2)
0	CW	X	0.0	0.0	1.0	0.00	221.9	±2.3%	±4.7%
		Y	0.0	0.0	1.0		232.7		
		Z	0.0	0.0	1.0		253.3		
10352-AAA	Pulse Waveform (200Hz, 10%)	X	1.51	60.00	5.57		60	±3.9%	±9.6%
		Y	1.57	60.00	5.55	10.00	60		
		Z	1.62	60.00	5.73		60		
10353-AAA	Pulse Waveform (200Hz, 20%)	X	70.00	72.00	7.00		80	±3.7%	±9.6%
		Y	22.00	70.00	7.00	6.99	80		
		Z	0.98	60.00	4.59		80		
10354-AAA	Pulse Waveform (200Hz, 40%)	X	0.12	140.14	0.34		95	±2.6%	±9.6%
		Y	0.57	60.00	2.92	3.98	95		
		Z	0.76	60.00	2.90		95		
10355-AAA	Pulse Waveform (200Hz, 60%)	X	2.08	159.90	2.51		120	±1.8%	±9.6%
		Y	15.56	147.46	8.41	2.22	120		
		Z	15.66	146.57	4.01		120		
10387-AAA	QPSK Waveform, 1 MHz	X	0.51	60.00	7.88		150	±5.2%	±9.6%
		Y	0.67	60.60	8.31	1.00	150		
		Z	0.62	60.40	8.39		150		
10388-AAA	QPSK Waveform, 10 MHz	X	1.15	62.13	10.95		150	±1.3%	±9.6%
		Y	1.27	62.41	11.04	0.00	150		
		Z	1.22	62.09	11.07		150		
10396-AAA	64-QAM Waveform, 100 kHz	X	1.84	65.88	16.63		150	±0.8%	±9.6%
		Y	1.91	66.08	16.48	3.01	150		
		Z	1.94	66.38	16.80		150		
10414-AAA	WLAN CCDF, 64-QAM, 40MHz	X	3.91	65.17	14.42		150	±5.6%	±9.6%
		Y	4.02	64.86	14.22	0.00	150		
		Z	4.04	65.19	14.49		150		

Note: For details on UID parameters see Appendix

The reported uncertainty of measurement is stated as the standard uncertainty of Measurement multiplied by the coverage factor *k*=2, which for a normal distribution Corresponds to a coverage probability of approximately 95%.

[A] The uncertainties of Norm X, Y, Z do not affect the E^2-field uncertainty inside TSL (see Page 5).
[B] Numerical linearization parameter: uncertainty not required.
[E] Uncertainly is determined using the max. deviation from linear response applying rectangular distribution and is expressed for the square of the field value.

In Collaboration with
s p e a g
CALIBRATION LABORATORY

CAICT

Add: No.52 HuaYuanBei Road, Haidian District, Beijing, 100191, China
Tel: +86-10-62304633-2117
E-mail: emf@caict.ac.cn http://www.caict.ac.cn

DASY/EASY – Parameters of Probe: EX3DV4 – SN: 7612

Sensor Model Parameters

	C1 fF	C2 fF	α V^{-1}	T1 $ms.V^{-2}$	T2 $ms.V^{-1}$	T3 ms	T4 V^{-2}	T5 V^{-1}	T6
X	14.29	102.05	32.25	2.46	0.00	4.90	0.61	0.00	1.02
Y	17.83	127.36	32.13	5.16	0.00	4.90	0.71	0.00	1.02
Z	16.51	118.08	32.29	6.12	0.00	4.90	0.77	0.00	1.02

Other Probe Parameters

Sensor Arrangement	Triangular
Connector Angle (°)	171.2
Mechanical Surface Detection Mode	enabled
Optical Surface Detection Mode	disable
Probe Overall Length	337mm
Probe Body Diameter	10mm
Tip Length	9mm
Tip Diameter	2.5mm
Probe Tip to Sensor X Calibration Point	1mm
Probe Tip to Sensor Y Calibration Point	1mm
Probe Tip to Sensor Z Calibration Point	1mm
Recommended Measurement Distance from Surface	1.4mm

In Collaboration with
s p e a g
CALIBRATION LABORATORY

CAICT

Add: No.52 HuaYuanBei Road, Haidian District, Beijing, 100191, China
Tel: +86-10-62304633-2117
E-mail: emf@caict.ac.cn http://www.caict.ac.cn

DASY/EASY – Parameters of Probe: EX3DV4 – SN:7612

Calibration Parameter Determined in Head Tissue Simulating Media

f [MHz][C]	Relative Permittivity [F]	Conductivity (S/m) [F]	ConvF X	ConvF Y	ConvF Z	Alpha[G]	Depth[G] (mm)	Unct. (*k*=2)
750	41.9	0.89	11.30	11.30	11.30	0.19	1.15	±13%
835	41.5	0.90	10.86	10.86	10.86	0.16	1.35	±13%
900	41.5	0.97	10.80	10.80	10.80	0.19	1.23	±13%
1750	40.1	1.37	9.16	9.16	9.16	0.36	0.86	±13%
1900	40.0	1.40	8.77	8.77	8.77	0.23	1.14	±13%
2100	39.8	1.49	8.70	8.70	8.70	0.22	1.12	±13%
2300	39.5	1.67	8.36	8.36	8.36	0.60	0.68	±13%
2450	39.2	1.80	8.10	8.10	8.10	0.66	0.68	±13%
2600	39.0	1.96	7.90	7.90	7.90	0.65	0.68	±13%
3300	38.2	2.71	7.40	7.40	7.40	0.49	0.86	±14%
3500	37.9	2.91	7.28	7.28	7.28	0.42	1.02	±14%
3700	37.7	3.12	7.05	7.05	7.05	0.42	1.05	±14%
3900	37.5	3.32	6.94	6.94	6.94	0.35	1.35	±14%
4100	37.2	3.53	6.88	6.88	6.88	0.30	1.30	±14%
4200	37.1	3.63	6.80	6.80	6.80	0.30	1.45	±14%
4600	36.7	4.04	6.60	6.60	6.60	0.45	1.20	±14%
4950	36.3	4.40	6.27	6.27	6.27	0.50	1.20	±14%
5250	35.9	4.71	5.71	5.71	5.71	0.50	1.30	±14%
5600	35.5	5.07	5.10	5.10	5.10	0.55	1.20	±14%
5750	35.4	5.22	5.21	5.21	5.21	0.55	1.20	±14%

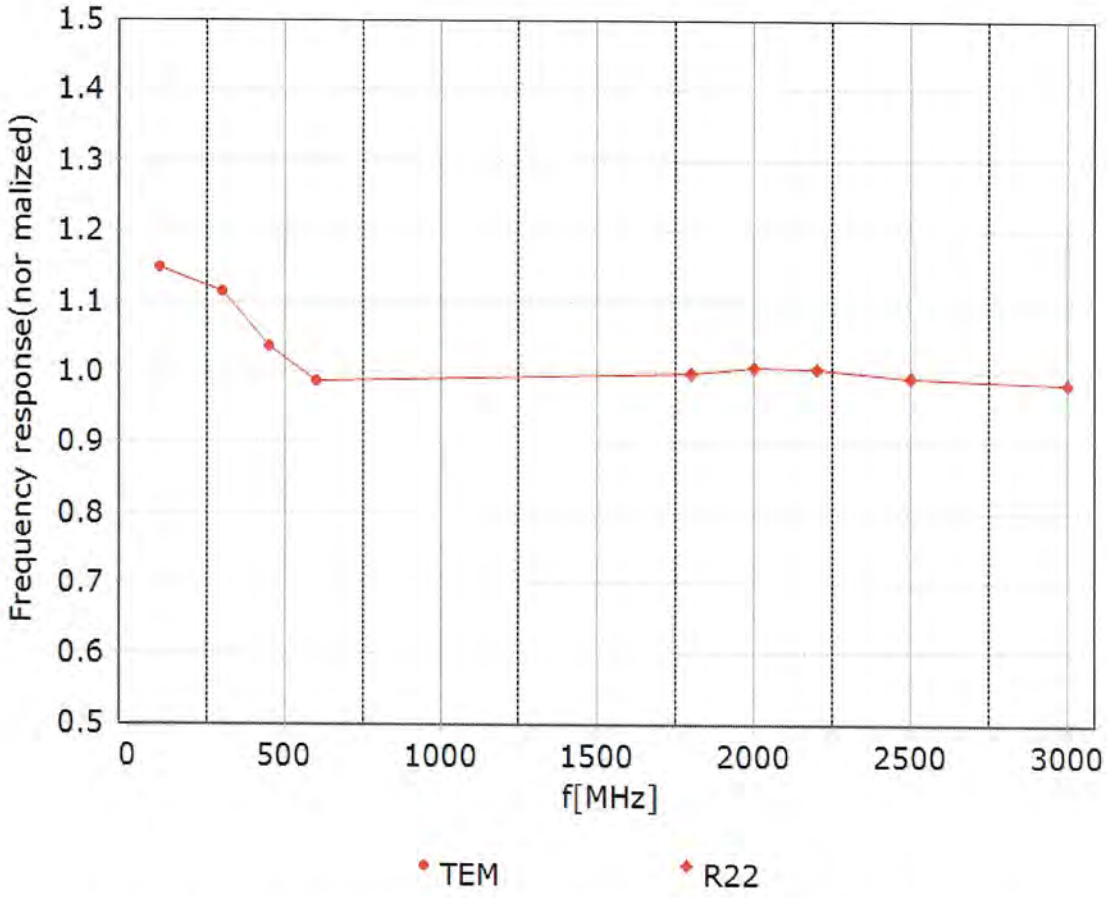
[C] Frequency validity above 300 MHz of ±100MHz only applies for DASY v4.4 and higher (Page 2), else it is restricted to ±50MHz. The uncertainty is the RSS of ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band. Frequency validity below 300 MHz is ± 10, 25, 40, 50 and 70 MHz for ConvF assessments at 30, 64, 128, 150 and 220 MHz respectively. Above 5 GHz frequency validity can be extended to ± 110 MHz.

[F] At frequency up to 6 GHz, the validity of tissue parameters (ε and σ) can be relaxed to ±10% if liquid compensation formula is applied to measured SAR values. The uncertainty is the RSS of the ConvF uncertainty for indicated target tissue parameters.

[G] Alpha/Depth are determined during calibration. SPEAG warrants that the remaining deviation due to the boundary effect after compensation is always less than ± 1% for frequencies below 3 GHz and below ± 2% for the frequencies between 3-6 GHz at any distance larger than half the probe tip diameter from the boundary.

Add: No.52 HuaYuanBei Road, Haidian District, Beijing, 100191, China
Tel: +86-10-62304633-2117
E-mail: emf@caict.ac.cn http://www.caict.ac.cn

Frequency Response of E-Field
(TEM-Cell: ifi110 EXX, Waveguide: R22)

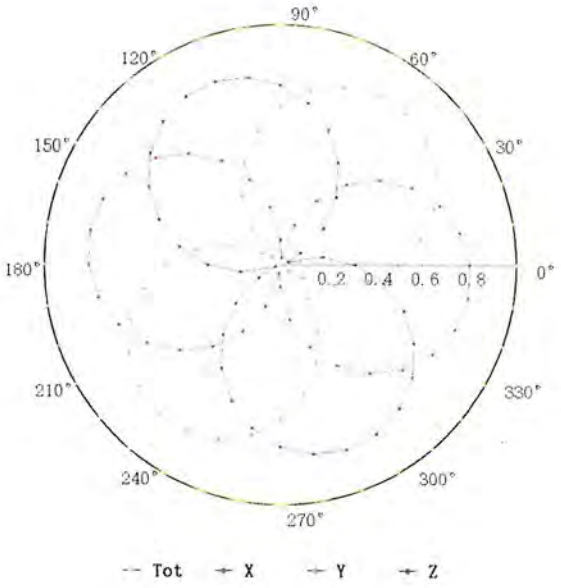


Uncertainty of Frequency Response of E-field: ±7.4% (*k*=2)

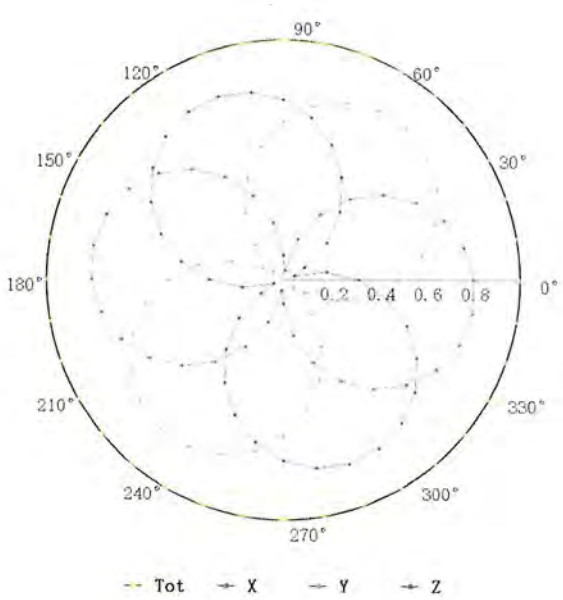
Add: No.52 HuaYuanBei Road, Haidian District, Beijing, 100191, China
Tel: +86-10-62304633-2117
E-mail: emf@caict.ac.cn http://www.caict.ac.cn

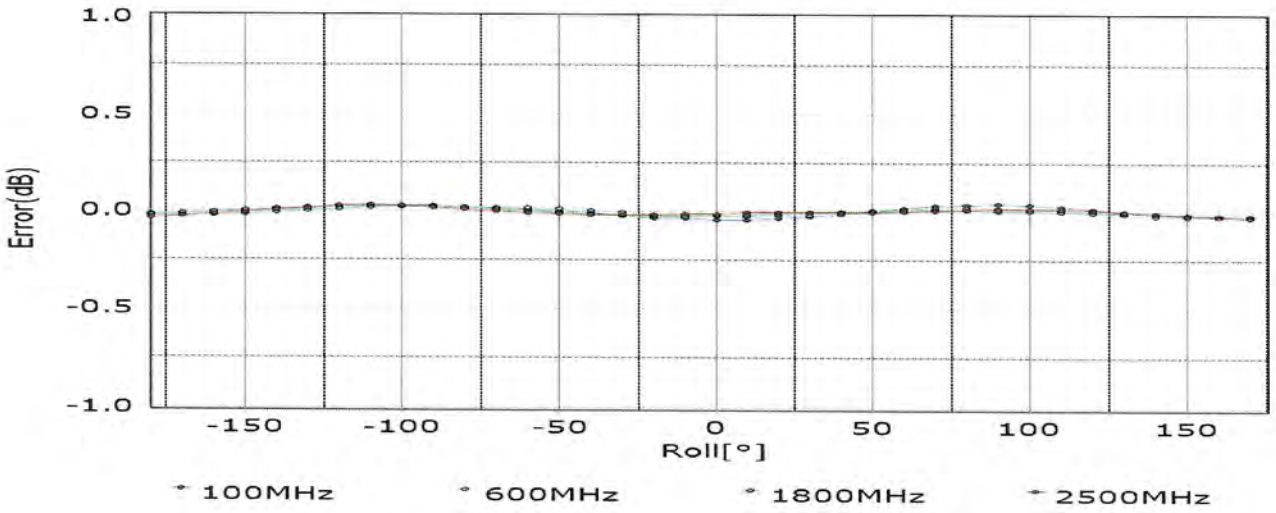
Receiving Pattern (Φ), θ=0°

f=600 MHz, TEM



f=1800 MHz, R22





Uncertainty of Axial Isotropy Assessment: ±1.2% (*k*=2)